

Notic of Referenc s Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination	
	09/749,917	CHANG ET AL.	
Examiner	Nikolas J. Uhlir	Art Unit	1773

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
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	M	US-			

FOREIGN PATENT DOCUMENTS

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	N	WO99/20812	04-1999	JP	Yin et al.	-----
	O					
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NON-PATENT DOCUMENTS

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